



7KH SURGXFWV DUHHG %S VKR JKR XS Ø HU  
 LV D VPDOO RXWOLHQH RERXS Ø IHDF HV XIRX  
 ,W FRQVLVWV RI D KLJK RXWSXW SRØE  
 WR D KLJK VSHHG SKRWRIG IFRG S WWDQ  
 SODVWLF :623 DQG JXHUSSDQW HGLW V DFC  
 D FOHDUDQFH RI • P W IDROG VDIQLE Ø Ø Ø  
 7KHUHIRUH LW PHHGV LQW X Ø DMLRQR EØ  
 RI LQWHUQDWLRQDO VDIHW\ VWDQGDUG  
 LQ SURJUDPPDEOH XFRVLDO DQYHUW  
 SRZHU VXSSOLHV



+LJK LVRODWLRQ 9506  
 &7,! 9  
 2SHUDWLQJ WHPSHUJHWXUH WR f &  
 5(\$+ 5R+6 FRPSOLDQFH  
 +%0 + \$ 00 0 &'0 &  
 &4& DSSURYHG  
 9'( DSSURYHG  
 8/ DSSURYHG

/( ')	2XWSXW
21	/
2))	+

7HP SHUDWXUH f &

Parameter	Symbol	Value	Unit
,QSXW	)RUZDUG &XUUHQW ,)		
	3HDN )RUZDUG &XUUHQW	7	\$
	5HYHUVH 9ROWDJH 95		
	,QSXW 3RZHU 'LVVLSDWLRQ	3	P:
2XWSXW	6XSSO\ 9ROWDJH &&	9	
	2XWSXW 9ROWDJH 92		

	2XWSXW & XUUHQW	2		
	2XWSXW 3RZHU 'LVVLSDWLRQ		3	P:
7RWDO 3RZHU 'LVVLSDWLRQ		3WRW		P:
,VRODWLRQ 9ROWDJH		9LVR	8	9UPV
2SHUDWLQJ 7HPSHUDWXUH		7RSU	a	
-XQFWLRQ 7HPSHUDWXUH		7M		
6WRUDJH 7HPSHUDWXUH		7VWJ	a	
6ROGHULQJ 7HPSHUDWXUH		7VRO		

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FIG.7: /RZ /HYHO 2XWDSJHWY9/RQ\$ PELHQ  
7HP SHUDWXUH

FIG.8: 3URSDJDWLRQ 'HOD\ YV /RDG  
5HVLVWDQFH

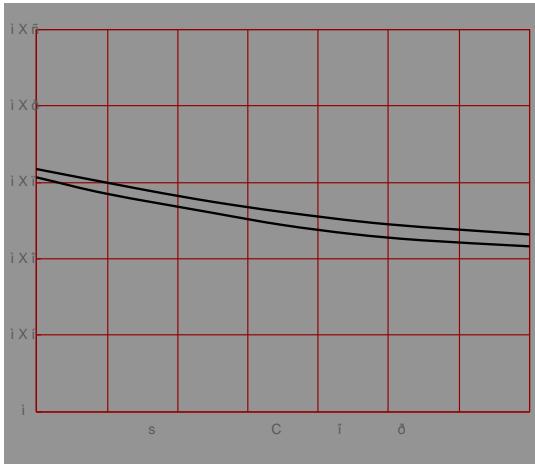


Fig.10: Test Circuit of tPHL, tPLH

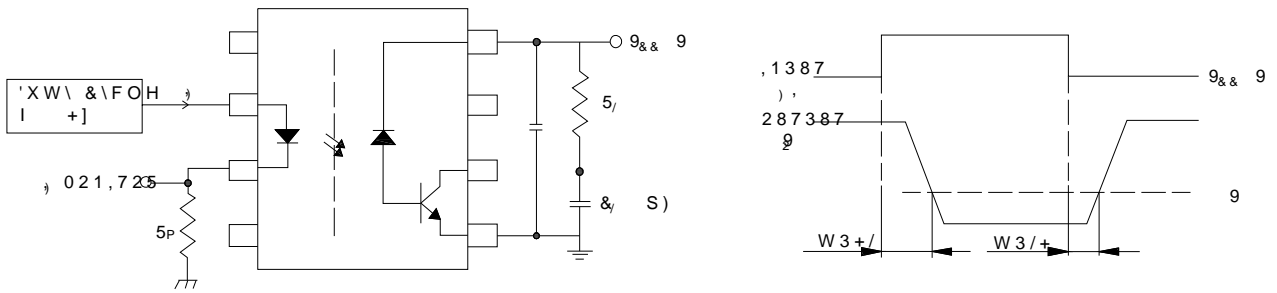
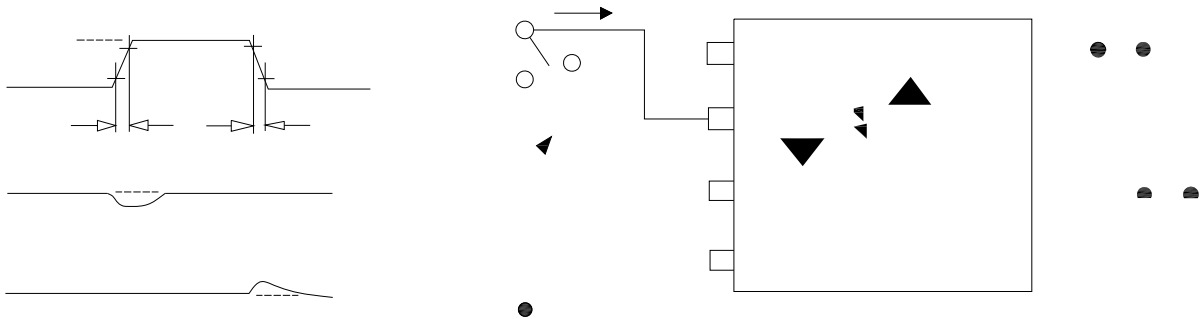
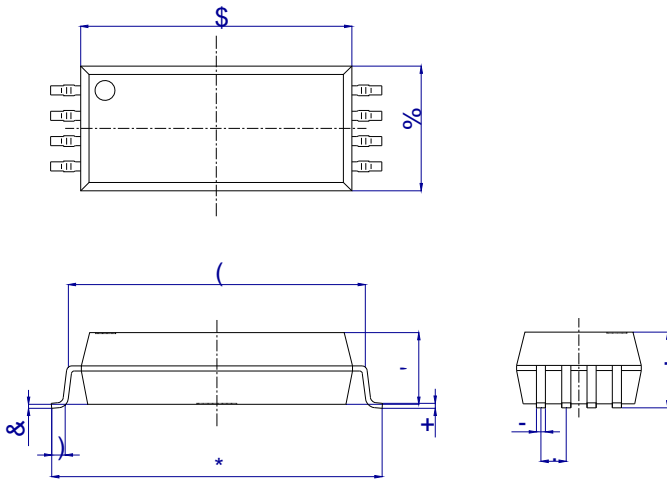
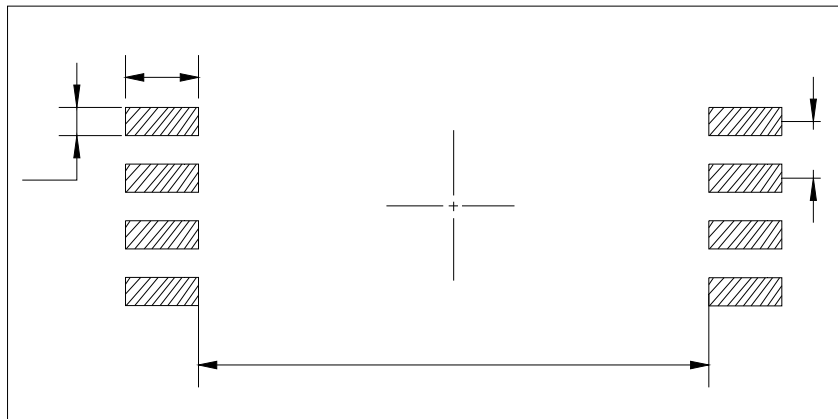


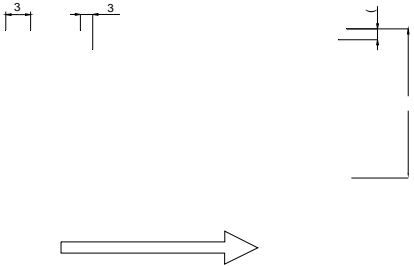
Fig.11: Test Circuit for Transient Immunity and Typical Waveforms

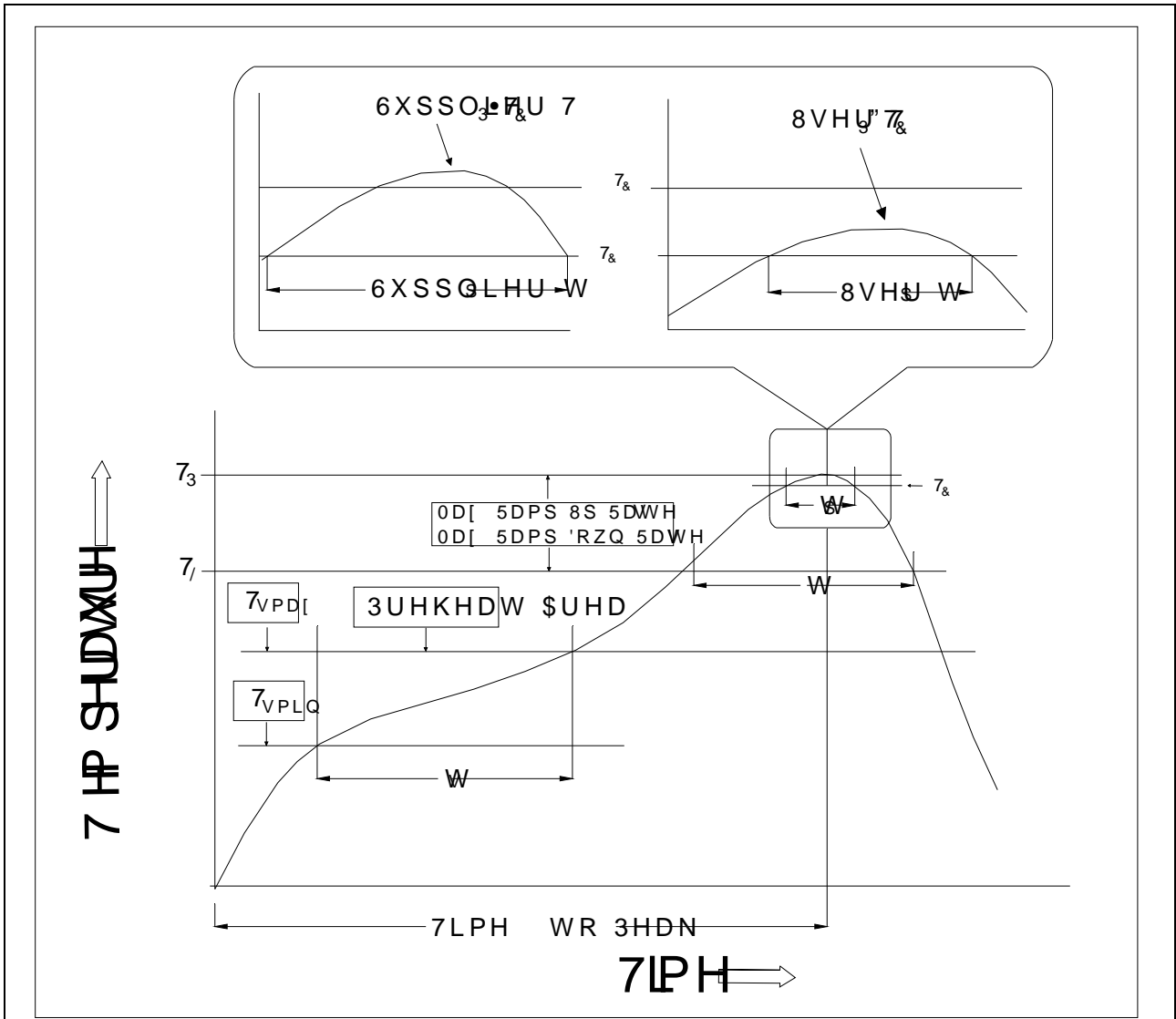




5HI	'LPHQVLRQV					
	0LOOLPHWHUV			,QFKHV		
	0LQ	7\ S	0D[	0LQ	7\ S	0D[
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Profile Feature	Sn-Pb Assembly Profile	Pb-Free Assembly Profile
7HP SHUDWXUH 0LQ	7VPLQ	
7HP SHUDWXUH 0D[	7VPD[	

1RWH

5HIORZ VROGHULQJ LV UHFRPPHQGHG/ DWKRVZQH QVHPSHWDWIXDQ WXB  
 \$YRLG GLUHFV FRQVWDH SVRPHQVZDQ QWRXUDFRUV H[FHHGLQJ LWV PD  
 VWRUDJH WHPSHUDWXUH  
 \$SSOLFDWLRQ RKHUSRYXENRQLWLSOHGDDWHG WHPSHUDWXUHV ,QV  
 VFHQDULRV DQHDPSSWLQRWRHFFHHG 1  
 (QVXUH WKH FRPSRQHQW KDV FRROHG SURDFHEWKDQZLXPSWHUDXHQ  
 PDQXIDFWXULQJ VWHSV  
 7KH FRPSRQHQW HQRV BQKHODUQKHQ VWRUHG XQGHU

06I OHYH G 06I S